


<b>Search Notes</b>  	<b>Application/Control No.</b>  10587010	<b>Applicant(s)/Patent Under Reexamination</b>  KUMAKI ET AL.
	<b>Examiner</b>  Dawn Garrett	<b>Art Unit</b>  1794

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EIC-1700 STIC structure search (see attached printout)	2/26/2009	D. Garrett

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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